

Notice of References Cited	Application/Control No. 10/582,330		Applicant(s)/Patent Under Reexamination SUMIYA, HITOSHI	
	Examiner SHENG HAN		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0039603	02-2003	Meng, Yue	423/446
*	B	US-3,148,161	09-1964	WENTORF JR ROBERT H et al.	252/502
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bernard, M. et al. "Non-Destructive Determination of the boron concentration of heavily doped metallic diamond thin films from Raman Spectroscopy." Diamond and Related Materials 13 (2004) 282-286
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.